IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Katsumi SUEMITSU et al.

Conf.

Application No. NEW NATIONAL PHASE

Group

Filed March 31, 2005

Examiner

MAGNETIC MEMORY AND MANUFACTURING METHOD OF THE SAME

INFORMATION DISCLOSURE STATEMENT (SUBMISSION CONCURRENT WITH THE FILING OF A NEW PATENT APPLICATION)

Assistant Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

March 31, 2005

Sir:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98, and in fulfillment of the duty of disclosure under 37 C.F.R. § 1.56, applicant(s) hereby submit(s) an Information Disclosure Statement for consideration by the Examiner.

I. LIST OF PATENTS, PUBLICATIONS OR OTHER INFORMATION

The patents, publications, or other information submitted for consideration by the Office are listed on PTO-1449, attached hereto.

II. COPIES

- Copies of the U.S. patents or publications are not submitted since the USPTO has waived their submission for applications filed after June 30, 2003.
- Submitted herewith is a legible copy of (i) each foreign patent; (ii) each publication or that portion which caused it to be listed; and (iii) all other information or that portion which caused it to be listed.
- This application is a National Phase of a PCT application. Some or all of the documents listed on the PTO-1449 are not enclosed because they were cited in the International Search Report and copies should have been forwarded from the International Search Authority pursuant to the trilateral agreement between the USPTO, EPO and JPO, or they are U.S. patents or U.S. published applications. If copies are needed, please contact the undersigned.

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III. CONCISE EXPLANATION OF THE RELEVANCE CONCINED TO SAME CONCI

DOCUMENTS IN THE ENGLISH LANGUAGE a. \boxtimes

The attached non U.S. patents, non U.S. patent application publications, foreign publications, or other information in the English language do not require a statement of relevancy.

DOCUMENTS NOT IN THE ENGLISH LANGUAGE b. \boxtimes

A concise explanation of the relevance of all patents, publications, or other information listed that is not in the English language is as follows:

οf the references are cited the specification.

冈 FOREIGN SEARCH REPORT OR ACTION C.

An English language version of the search report or action that indicates the degree of relevance found by the foreign office is attached, thereby satisfying the requirement for а explanation. See MPEP 609(A)(3).

d. OTHER

The following additional information is provided for the Examiner's consideration.

FEES

Information Disclosure Statement This being filed is filing of concurrently with the a new patent application; therefore, no fee is required.

If The Examiner has any questions concerning this IDS, he/she is requested to contact the undersigned.

Respectfully submitted,

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Enclosures:	\boxtimes	Form PTO-1449(s)
	\boxtimes	Documents
	\boxtimes	Foreign Search Report
		Other:

EXAMINER:

Sheet 1 of 1

Attorney Docket No.: Application No.: INFORMATION DISCLOSURE CITATION 8022-1094 **NEW NATIONAL PHASE** IN AN APPLICATION Applicant: Katsumi SUEMITSU t al. (Use several sheets if necessary) Filing Date: Group Art Unit: March 31, 2005 **U.S. PATENT DOCUMENTS Document Number** Examiner Date Name Class Subclass Filing date Initial (if appropriate) 2002/0044396 4/18/2002 AMANO et al. 2001/0025978 10/4/2001 nakao 6,297,983 10/2/2001 **BHATTACHARYYA FOREIGN PATENT DOCUMENTS** Examiner Document Number Translation Class Date Country Subclass Initial Yes No 2003-243630 8/29/2003 **JAPAN** 1 248 305 10/9/2002 EUROPE 2002-208682 7/26/2002 **JAPAN** 2002-124717 4/26/2002 **JAPAN** 10-4227 1/6/1998 JAPAN 11-330585 11/30/1999 **JAPAN** 2002-9367 1/11/2002 JAPAN OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) k. tsuji ET AL., "0.1µM-rule MRAM Development using Double-Layered Hard Mask", 2001 IEEE

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

DATE CONSIDERED

International Electron Devices Meeting, pages 799 to 802

^{*} English language abstract provided for the Examiner's convenience